

November 2006

# FDZ493P

# P-Channel 2.5V Specified PowerTrench<sup>®</sup> BGA MOSFET –20V, –4.6A, 46m $\Omega$

#### **Features**

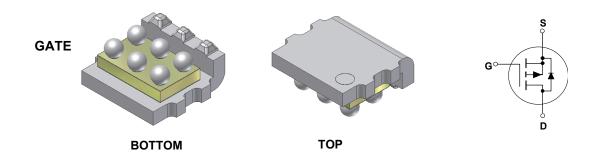
- Max  $r_{DS(on)}$  = 46m $\Omega$  at  $V_{GS}$  = -4.5V,  $I_D$  = -4.6A
- Max  $r_{DS(on)} = 72m\Omega$  at  $V_{GS} = -2.5V$ ,  $I_D = -3.6A$
- Occupies only 2.25 mm<sup>2</sup> of PCB area. Less than 50% of the area of SSOT-6.
- Ultra-thin package: less than 0.80 mm height when mounted to PCB
- Outstanding thermal transfer characteristics:4 times better than SSOT-6.
- Ultra-low Qg x r<sub>DS(on)</sub> figure-of-merit.
- RoHS Compliant.

### **General Description**

Combining Fairchild's advanced 2.5V specified PowerTrench® process with state of the art BGA packaging process, the FDZ493P minimizes both PCB space and  $r_{DS(on)}.$  This BGA MOSFET embodies a breakthrough in packaging technology which enables the device to combine excellent thermal transfer characteristics, high current handing capability,ultra-low profile packaging, low gate charge, and low  $r_{DS(on)}.$ 

# **Application**

- Battery management
- Load switch
- Battery protection



# MOSFET Maximum Ratings T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Par	ameter		Ratings	Units
$V_{DS}$	Drain to Source Voltage			-20	V
$V_{GS}$	Gate to Source Voltage			±12	V
	Drain Current -Continuous	T <sub>A</sub> = 25°C	(Note 1a)	-4.6	۸
'D	-Pulsed			-10	_ A
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25°C	(Note 1a)	1.7	W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range			-55 to +150	°C

#### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	72	°C/W

#### **Package Marking and Ordering Information**

Device Marking	Device	Reel Size	Tape Width	Quantity
E	FDZ493P	7"	8mm	3000 units

# **Electrical Characteristics** $T_A = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0V$	-20			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D$ = -250 $\mu$ A, referenced to 25°C		-13		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = -16V, \ V_{GS} = 0V$			-1	μΑ
$I_{GSS}$	Gate to Source Leakage Current	$V_{GS} = \pm 12V, V_{DS} = 0V$			±100	nA

#### On Characteristics (note 2)

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = -250 \mu A$	-0.6	-0.8	-1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = -250\mu\text{A}$ , referenced to 25°C		3		mV/°C
		$V_{GS} = -4.5V$ , $I_D = -4.6A$		36	46	
r <sub>DS(on)</sub>	Drain to Source On Resistance	$V_{GS} = -2.5V$ , $I_D = -3.6A$		58	72	mΩ
		$V_{GS} = -4.5V$ , $I_D = -4.6A$ , $T_J = 125$ °C		47	65	
I <sub>D(on)</sub>	On to State Drain Current	$V_{GS} = -4.5V, V_{DS} = -5V$	-10			Α
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = -5V, I_D = -4.6A$		13		S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = -10V, V <sub>GS</sub> = 0V, f = 1MHz	754	pF
C <sub>oss</sub>	Output Capacitance		167	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	- 1 - 11VII 12	92	pF
$R_g$	Gate Resistance	f = 1MHz	6	Ω

#### **Switching Characteristics** (note 2)

t <sub>d(on)</sub>	Turn-On Delay Time		11	20	ns
t <sub>r</sub>	Rise Time	$V_{DD} = -10V, I_{D} = -1A$ $V_{GS} = -4.5V, R_{GEN} = 6\Omega$	10	20	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	V <sub>GS</sub> = -4.5V, K <sub>GEN</sub> = 012	22	35	ns
t <sub>f</sub>	Fall Time		17	31	ns
$Q_{g(TOT)}$	Total Gate Charge at 10V	$V_{DS} = -10V, I_{D} = -4.6A$	7.5	11	nC
$Q_{gs}$	Gate to Source Gate Charge	V <sub>GS</sub> = -4.5V	1.5		nC
$Q_{gd}$	Gate to Drain "Miller" Charge		2.0		nC

#### **Drain-Source Diode Characteristics**

$I_S$	Maximum continuous Drain-Source Diode Forward Current				-1.4	Α
$V_{SD}$	Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_S = -1.4A$ (Note 2)		-0.7	-1.2	V
t <sub>rr</sub>	Reverse Recovery Time	1 - 4 0 4 - 4 0 0 4 / -		17		ns
Q <sub>rr</sub>	Reverse Recovery Charge	$I_F = -4.6A$ , di/dt = 100A/ $\mu$ s		5		nC

 $R_{0JA}$  is determined with the device mounted on a  $1in^2$  pad 2 oz copper pad on a  $1.5 \times 1.5$  in. board of FR-4 material. The thermal resistance from the junction to the circuit board side of the solder ball,  $R_{0JB}$  is defined for reference. For  $R_{0JC}$  the thermal reference point for the case is defined as the top surface of the copper chip carrier.  $R_{0JC}$  and  $R_{0JB}$  are guaranteed by design while  $R_{0JA}$  is determined by the user's board design.



a. 72°C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper,1.5"

X 1.5" X 0.062" thick PCB



b. 157°C/W when mounted on a minimum pad of 2 oz copper

<sup>2:</sup> Pulse Test: Pulse Width <  $300\mu$ s, Duty cycle < 2.0%.

## Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

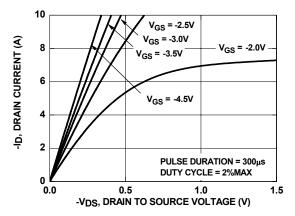


Figure 1. On Region Characteristics

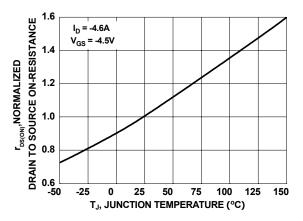


Figure 3. Normalized On Resistance vs Junction Temperature

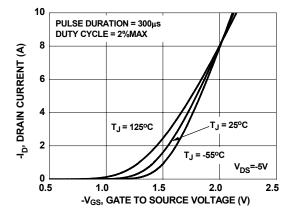


Figure 5. Transfer Characteristics

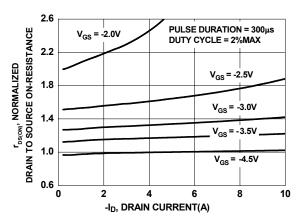


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

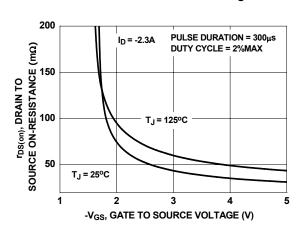


Figure 4. On-Resistance vs Gate to Source Voltage

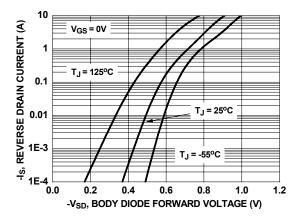


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

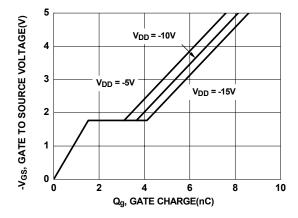


Figure 7. Gate Charge Characteristics

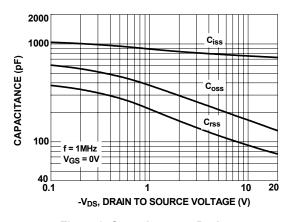


Figure 8. Capacitance vs Drain to Source Voltage

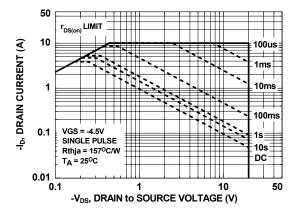


Figure 9. Forward Bias Safe Operating Area

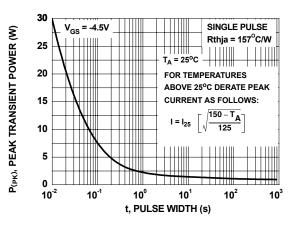


Figure 10. Single Pulse Maximum Power Dissipation

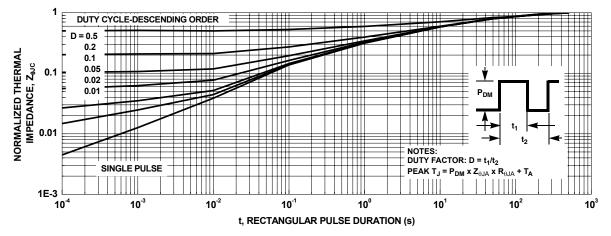
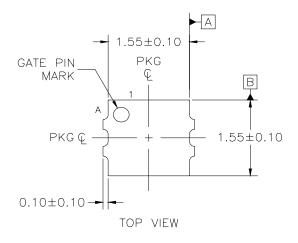
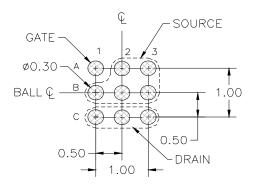


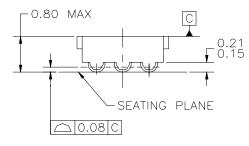
Figure 11. Transient Thermal Response Curve

# **Dimensional Pad and Layout**

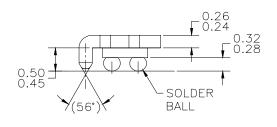




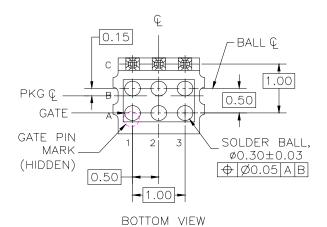
LAND PATTERN RECOMMENDATION



FRONT VIEW



SIDE VIEW



NOTES: UNLESS OTHERWISE SPECIFIED

- A) ALL DIMENSIONS ARE IN MILLIMETERS.
- B) NO JEDEC REGISTRATION REFERENCE AS OF JULY 1999.
- C) BALL/STUD CONFIGURATION TABLE

TERMINAL ID	DESIGNATION	TERMINAL TYPE
C1,C2,C3	DRAIN	COPPER STUD
A1	GATE	BALL
A2,A3,B1,B2,B3	SOURCE	BALL

BGA09CREVC



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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

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